EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	835	(714/30).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/07/30 13:00
L2	1794	(714/25).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/07/30 13:05
L3	80	(714/29).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/07/30 13:05
L4	892	(714/733).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/07/30 13:05
L5	25192	(device-under-test or DUT or (device adj under adj test))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:10
L6	2	5 same (scan-pin or (non-scan adj pin))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:20
L7	2	5 and (scan-pin or (non-scan adj pin))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 14:36
L8	1796	pin-group$4 or (pin adj group$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:19

L9	59	5 same 8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:19
L10	2	9 and (scan-pin or (non-scan adj pin))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:52
L11	1460	(device-under-test or DUT or (device adj under adj test)) near2 pin	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:21
L12	46	9 and L11	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:21
L13	0	(hildebrand-andrew$).in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 14:33
L14	16	(hildebrant-andrew$).in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 14:33
L15	2	8 and 5 and (scan-pin or (non-scan adj pin))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 14:36
S1	1720	(714/25).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:39

S2	2157	hildebrand.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 14:32
S3	0	(hildebrand-andrew$).in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:14
S4	15	(hildebrant-andrew$).in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:22
S5	13522	(test$4 or diagnos$4 or analyz$4 or analis$4) same (device-under-test or DUT or (device adj under adj test))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:26
S6	64	S5 same (data adj file)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:26
S7	1365	(device-under-test or DUT or (device adj under adj test)) near2 pin	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:08
S8	13	S6 and S7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:32
S9	609	scan-pin or non-scan	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:10

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S10	5	S5 same S9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:33
S11	3	S10 not S4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:35
S12	14	pin-group$4 or (pin adj proup$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:16
S13	12	S12 not (S4 or S10)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:37
S14	79	(714/29).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:39
S15	789	(714/30).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/30 13:00
S16	2206	(714/733-736).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:40
S17	1829	(714/738-742).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/06 16:41

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#2	((device under test<in>metadata) <and> (scan-pin<in>metadata))<and> (non-scan pin<in>metadata)	0
#3	(((test or analyze or analisys)<in>metadata) <and> (scan-pin<in>metadata))<and> (pin group<in>metadata)	0

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181 Component and integration testing: Substra: a framework for automatic generation of integration tests ☐
Hai Yuan, Tao Xie
May 2006   **Proceedings of the 2006 international workshop on Automation of software test AST '06**
Publisher: ACM Press
Full text available: 📄 pdf(337.91 KB)   Additional Information: full citation, abstract, references, index terms

> A component-based software system consists of well-encapsulated components that interact with each other via their interfaces. Software integration tests are generated to test the interactions among different components. These tests are usually in the form of sequences of interface method calls. Although many components are equipped with documents that provide informal specifications of individual interface methods, few documents specify component interaction constraints on the usage of these in ...
>
> **Keywords**: integration testing, software testing, test generation

182 (Special session) invited talks: mixed signal test: A novel LCD driver testing technique using logic test channels ☐
Chauchin Su, Wei-Juo Wang, Chih-Hu Wang, IS Tseng
January 2003 **Proceedings of the 2003 conference on Asia South Pacific design automation ASPDAC**
Publisher: ACM Press
Full text available: 📄 pdf(200.50 KB)   Additional Information: full citation, abstract, references

> This paper proposes a novel voltage measurement technique for LCD driver testing by the use of logic test channel of an ATE. The method is able to achieve less than 1mV error with the presence of 32mV RMS noise.

183 Challenges in the Design of a Scalable Data-Acquisition and Processing System-on-Silicon ☐
January 2002 **Proceedings of the 2002 conference on Asia South Pacific design automation/VLSI Design**
Publisher: IEEE Computer Society
Full text available: 📄 pdf(155.29 KB) 📑
Publisher Site   Additional Information: full citation, abstract

> Increasing complexity of the functionalities and the resultant growth in number of gates integrated in a

Interference 9 10/620191

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L16	2	8 and 5 and (scan-pin or (non-scan adj pin))	US-PGPUB; USPAT	OR	ON	2006/07/30 15:25